

آزما صنعت گراد



نماینده انحصاری کمپانی **Mahr** آلمان

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EXACTLY

MarSurf



MarSurf WM 100*

3D Measurement System - White Light Interferometer

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- High precision with sub nanometer resolution
- Ideal for optical, reflecting and technical surfaces
- 2D surface analysis and measurement evaluation
- Topographic 3D surface analysis and measurement evaluation
- Fast measurement - short measuring time

* Instrument shown with optional angular tilt table

MarSurf WM 100

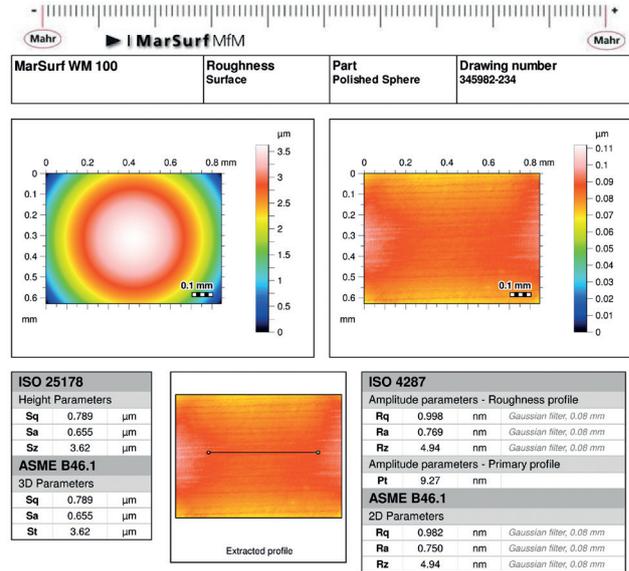
Description

Surface scanning sensor ideally suited for fast-paced measurement of smallest to medium sized surface details, like roughness measurement in the sub nanometer range. Excellent, high resolution reproduction of even microscopic surface details.

- Microscopic technology dedicated to the reproduction of tiny surface structures up to the physical limit.
- Combined phase measured and vertical scanning technology with high performance objectives gives fast, precise and reliable results.
- Robust, maintenance free, built for long service life.
- Complete assortment of premium quality objectives available
- 120 mm xy table allows precise movement of measuring object. Additional angular tilt table available.
- Optional evaluation software **MarSurf MfM** and **MarSurf MfM plus**.



Evaluation



Measuring Report: Roughness Measurement

- Measurement of topography, height, shape and position of surface structures.
- Standardized 3D surface parameters and 2D roughness parameters can easily be evaluated with e.g. the MarSurf MfM software along freely selectable lines, surfaces or surface sections. It further supports a large variety of 3D-result views.

MarSurf WM 100 - Technical Data

	Standard Optics	Optional Optics
Light source	High performance LED, $\lambda = 505$ nm	High performance LED, $\lambda = 505$ nm
Measuring range	100 μm (alternative: 250 μm or 400 μm)	100 μm (alternative: 250 μm or 400 μm)
Lens	20x	2.5x - 5x - 10x - 50x - [100x]
Numerical aperture	0.4	from 0.075 to 0.7
Working distance	4.7 mm	from 10.3 to 2.0 mm
Field of view	890 μm x 655 μm	7120 μm x 5340 μm - 178 μm x 134 μm
Resolution (X; Y)	1.16 μm	from 9.24 μm to 0.23 μm (geometrical)
Resolution (Z)	0.1 nm	1.0 nm (2.5 - 10x); 0.1 nm (20 - 100x)

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